. reescale Semiconductor

Technical Data

RF Power Field Effect Transistor Array

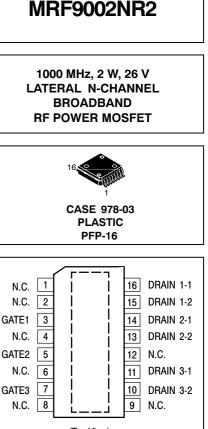
N-Channel Enhancement-Mode Lateral MOSFET

Designed for broadband commercial and industrial applications with frequencies to 1000 MHz. The high gain and broadband performance of this device make it ideal for large-signal, common-source amplifier applications in 26 volt base station equipment. The device is in a PFP-16 Power Flat Pack package which gives excellent thermal performances through a solderable backside contact.

- Typical Performance at 960 MHz, 26 Volts Output Power — 2 Watts Per Transistor Power Gain — 18 dB Efficiency — 50%
- Capable of Handling 10:1 VSWR, @ 26 Vdc, 960 MHz, 2 Watts CW **Output Power**

Features

- Designed for Maximum Gain and Insertion Phase Flatness
- **Excellent Thermal Stability**
- Characterized with Series Equivalent Large-Signal Impedance Parameters
- **RoHS** Compliant
- In Tape and Reel. R2 Suffix = 1,500 Units per 16 mm, 13 inch Reel.



(Top View) Note: Exposèd backside flag is source terminal for transistors.

N.C.

N.C.

Figure 1. Pin Connections

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Table 1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V _{DSS}	-0.5, +65	Vdc
Gate-Source Voltage	V _{GS}	-0.5, +15	Vdc
Total Dissipation Per Transistor @ $T_C = 25^{\circ}C$	PD	4	W
Storage Temperature Range	T _{stg}	-65 to +150	°C
Operating Junction Temperature	TJ	150	°C

Table 2. Thermal Characteristics

Characteristic	Symbol	Value ⁽¹⁾	Unit
Thermal Resistance, Junction to Case, Single Transistor	$R_{\theta JC}$	12	°C/W

Table 3. Moisture Sensitivity Level

Test Methodology	Rating	Package Peak Temperature	Unit
Per JESD 22-A113, IPC/JEDEC J-STD-020	3	260	°C

1. MTTF calculator available at http://www.freescale.com/rf. Select Tools/Software/Application Software/Calculators to access the MTTF calculators by product.

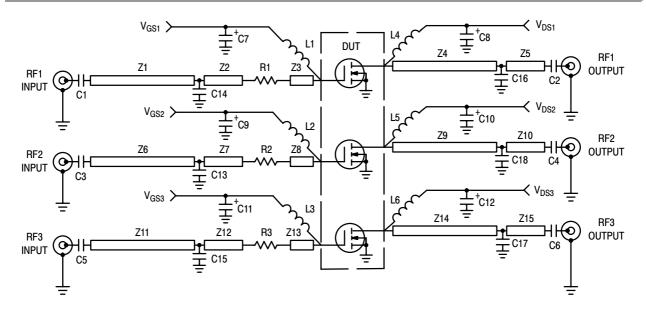
NOTE - CAUTION - MOS devices are susceptible to damage from electrostatic charge. Reasonable precautions in handling and packaging MOS devices should be observed.



Table 4. Electrical Characteristics (T_C = 25° C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Мах	Unit
On Characteristics					
Gate Threshold Voltage (V_{DS} = 10 Vdc, I_D = 20 μ Adc)	V _{GS(th)}	2.4		4	Vdc
Gate Quiescent Voltage (V _{DS} = 26 Vdc, I _D = 25 mAdc)	V _{GS(Q)}	3	_	5	Vdc
Drain-Source On-Voltage (V _{GS} = 10 Vdc, I _D = 0.1 Adc)	V _{DS(on)}		0.3	_	Vdc
unctional Tests (Per Transistor in Freescale Test Fixture, 5	i0 ohm system)	I		1	1
Common-Source Amplifier Power Gain @ P1dB (V_{DD} = 26 Vdc, I_{DQ} = 25 mA, f = 960.0 MHz)	G _{ps}	15	18	—	dB
Drain Efficiency @ P1dB (V _{DD} = 26 Vdc, I _{DQ} = 25 mA, f = 960.0 MHz)	η	35	50	_	%
Input Return Loss @ P1dB (V _{DD} = 26 Vdc, I _{DQ} = 25 mA, f = 960.0 MHz)	IRL	—	-15	-9	dB
Power Output, 1 dB Compression Point (V _{DD} = 26 Vdc, I _{DQ} = 25 mA, f = 960.0 MHz)	P _{1dB}	34	37	_	dBm





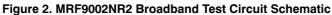
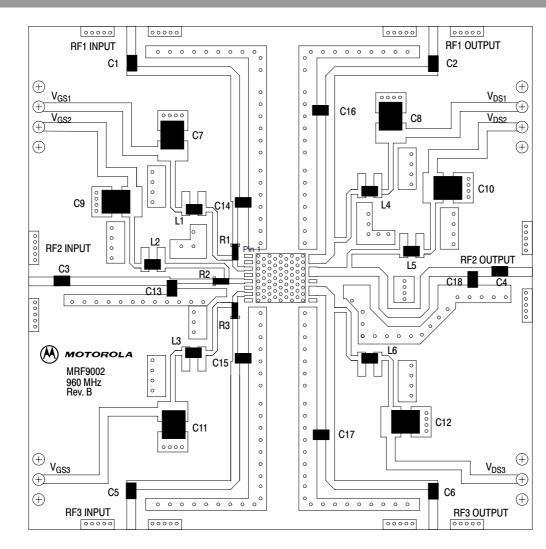


Table 5.	MRF9002NR2	Broadband Te	st Circuit	Component l	Designations and	Values
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Designators	Description
C1-C6	33 pF Chip Capacitors (0805)
C7-C12	1.0 μF, 35 V Tantalum Capacitors, B Case, Kemet
C13	8.2 pF Chip Capacitor (0805)
C14, C15	10 pF Chip Capacitors (0805)
C16, C17	2.7 pF Chip Capacitors (0805)
C18	3.3 pF Chip Capacitor (0805)
L1-L6	12 nH Chip Inductors (0805)
R1-R3	0 Ω Chip Resistors (0805)
Z1, Z11	1.16 x 28.5 mm Microstrip
Z2, Z7, Z12	0.65 x 5.6 mm Microstrip
Z3, Z8, Z13	0.65 x 2.6 mm Microstrip
Z4, Z14	1.16 x 19.5 mm Microstrip
Z5, Z15	1.16 x 17.5 mm Microstrip
Z6	1.16 x 12.9 mm Microstrip
Z9	1.16 x 27.2 mm Microstrip
Z10	1.16 x 4.3 mm Microstrip
PCB	Etched Circuit Board
Raw PCB Material	Rogers RO4350, 0.020", 2.5", x 2.5", ϵ_r = 3.5
Bedstead	Copper Heatsink

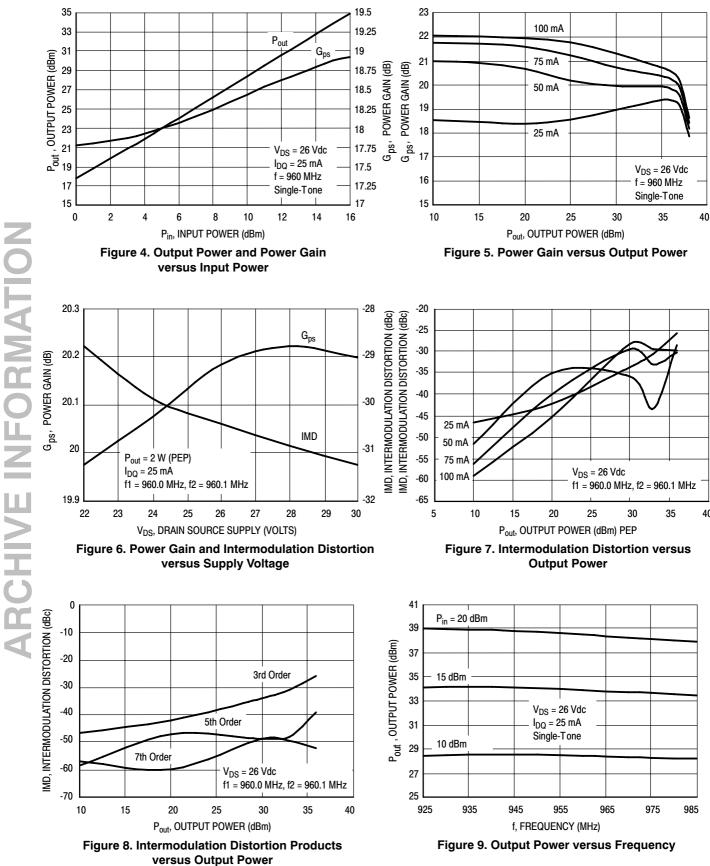


Freescale has begun the transition of marking Printed Circuit Boards (PCBs) with the Freescale Semiconductor signature/logo. PCBs may have either Motorola or Freescale markings during the transition period. These changes will have no impact on form, fit or function of the current product.

Figure 3. MRF9002NR2 Broadband Test Circuit Component Layout



TYPICAL CHARACTERISTICS





TYPICAL CHARACTERISTICS



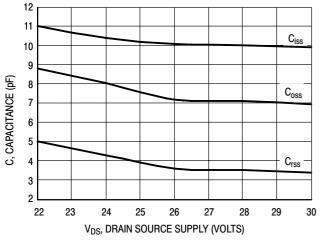
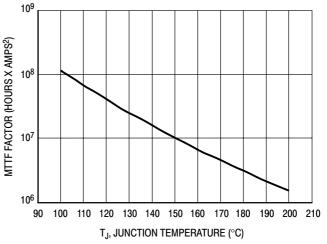


Figure 10. Capacitance versus Drain Source Voltage

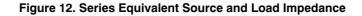


This above graph displays calculated MTTF in hours x ampere² drain current. Life tests at elevated temperatures have correlated to better than $\pm 10\%$ of the theoretical prediction for metal failure. Divide MTTF factor by $I_D{}^2$ for MTTF in a particular application.

Figure 11. MTTF Factor versus Junction Temperature



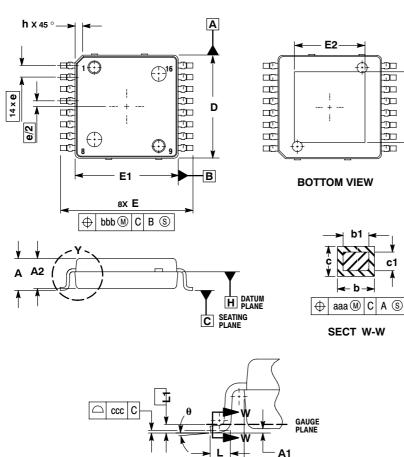
$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	5 5 12 5	55 MHz purce Hz 14 985 MHz 2 4 1 = 925 MHz 3 3 5 3 5 3 5 3 5 3 5 5 5 5 5 5 5 5 5 5 5 5 5	T 2 925 MHz Zload 985 MHz		
			17417		+
	_D = 26 V, I _{DQ} = 25 mA, P		ו		- 3
f MHz	Z _{source} Ω	Z _{load} Ω			
925	4.5 + j13.3	23.4 + j9.2			
960	4.3 + j15.3	23.2 + j10.4			
985	4.1 + j15.8	23.0 + j11.1		Z _{source} = Test circuit impedance as measured from	ľ
	Transistor 1			gate to ground.	
	_D = 26 V, I _{DQ} = 25 mA, P		ı	Z _{load} = Test circuit impedance as measured	
f MHz	z_{source}	Z _{load} Ω		from drain to ground.	
925	6.0 + j12.3	19.7 + j27.8			
925 960					
	6.0 + j12.3	19.7 + j27.8		Input Matching Nutrice Output Under Test Natching	1
960 985	6.0 + j12.3 5.9 + j14.3 5.8 + j16.5 Transistor 2	19.7 + j27.8 22.0 + j23.9 22.5 + j25.4			
960 985	6.0 + j12.3 5.9 + j14.3 5.8 + j16.5 Transistor 2 D = 26 V, I _{DQ} = 25 mA, P,	19.7 + j27.8 22.0 + j23.9 22.5 + j25.4 out = 2 W PEP		Matching Under Test Matching	l
960 985	6.0 + j12.3 5.9 + j14.3 5.8 + j16.5 Transistor 2	19.7 + j27.8 22.0 + j23.9 22.5 + j25.4		Matching Network Matching Network	
960 985 V _{DD}	6.0 + j12.3 5.9 + j14.3 5.8 + j16.5 Transistor 2 0 = 26 V, I _{DQ} = 25 mA, P, Z source	19.7 + j27.8 22.0 + j23.9 22.5 + j25.4 _{put} = 2 W PEP Z load		Matching Under Test Matching	
960 985 V _{DD} f MHz	$6.0 + j12.3$ $5.9 + j14.3$ $5.8 + j16.5$ Transistor 2 $D = 26 \text{ V}, \text{ I}_{DQ} = 25 \text{ mA}, \text{ P},$ C_{Source}	19.7 + j27.8 22.0 + j23.9 22.5 + j25.4 put = 2 W PEP Z _{load} Ω		Matching Network Matching Network	
960 985 V _{DD} f MHz 925	$6.0 + j12.3$ $5.9 + j14.3$ $5.8 + j16.5$ Transistor 2 $0 = 26 \text{ V, } \text{I}_{\text{DQ}} = 25 \text{ mA, P}$ $\frac{\textbf{Z}_{\text{source}}}{\Omega}$ $4.3 + j12.2$	19.7 + j27.8 22.0 + j23.9 22.5 + j25.4 out = 2 W PEP Z _{load} Ω 23.1 + j6.5		Matching Network Matching Network	



RF Device Data Freescale Semiconductor



PACKAGE DIMENSIONS



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DETAIL Y

CASE 978-03 ISSUE C PLASTIC PFP-16

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- DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994.
 DATUM PLANE. +I- IS LOCATED AT BOTTOM OF LEAD AND IS COINCIDENT WITH THE LEAD WHERE THE LEAD EXITS THE PLASTIC BODY AT THE BOTTOM OF THE PARTING LINE.
 DIMENSIONS D AND E1 DO NOT INCLUDE MOLD PROTRUSION. ALLOWABLE PROTRUSION IS 0.250 PER SIDE. DIMENSIONS D AND E1 DO INCLUDE MOLD MISMATCH AND ARE DETERMINED AT DATUM PLANE -H-.
 DIMENSION & DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR
- PROTRUSION. ALLOWABLE DAMBAR PROTRUSION IS 0.127 TOTAL IN EXCESS OF THE b DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 6. DATUMS -A- AND -B- TO BE DETERMINED AT

	MILLIMETERS				
DIM	MIN	MAX			
Α	2.000	2.300			
A1	0.025	0.100			
A2	1.950	2.100			
D	6.950	7.100			
D1	4.372	5.180			
E	8.850	9.150			
E1	6.950	7.100			
E2	4.372	5.180			
L	0.466	0.720			
L1	0.250 BSC				
b	0.300	0.432			
b1	0.300	0.375			
C	0.180	0.279			
c1	0.180	0.230			
е	0.800 BSC				
h		0.600			
θ	0 °	7°			
aaa	0.2	200			
bbb	0.2	200			
CCC	0.100				



REVISION HISTORY

The following table summarizes revisions to this document.

Revision	Date	Description
8	Dec. 2009	Data sheet archived. Part no longer manufactured.



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